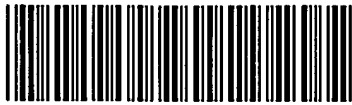


Search Notes

Application/Control No.

09/274,015

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

HEBERT ET AL.

Art Unit

1732

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|-----------|----------|
| updated | | 6/13/2005 | EHL |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 264 | 255 | 6/13/2005 | EHL |
| | 275, | | |
| | 279.1 | | |
| | | | |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|-----------------------|-----------|------|
| east | 6/13/2005 | EHL |
| reviewed parent cases | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |